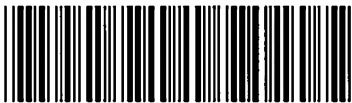


**Search Notes**

Application/Control No.

10/766,725

Examiner

Chuck Huynh

Applicant(s)/Patent under  
Reexamination

CHOI ET AL.

Art Unit

2617

**SEARCHED**

Class	Subclass	Date	Examiner
Updated	Search	11/10/2006	4H
455	411	11/10/2006	4H

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Class/Subclass	11/10/2006	4H
Revision of previous art	11/10/2006	4H
Combined Text search	11/10/2006	4H